



## Correction to: An improved adaptive sampling strategy for freeform surface inspection on CMM

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### Correction to: Int J Adv Manuf Technol.

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The original version of this article contained a mistake. Yincun Sang has been corrected to Yicun Sang. The presentation is corrected above.

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The online version of the original article can be found at <https://doi.org/10.1007/s00170-018-1612-y>

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